Subst. Form PTO-1449	Atty. Docket No.: RPS9200101720S1	(IRA-10-5709)	Serial No.: To be assigned	
APPLICANT'S INFORMATION DISCLOSURE STATEMENT				
	Applicant: Atoji et al			
	Filing Date: Herewith		Group: To be assigned 219	

## **U.S. PATENT DOCUMENTS**

Initial*		Document No.	Date	Name	Class	Subcl.	Filing Date
MPF	AA	5,815,688	09/29/1998	Averill	395	500	10/09/1996
YPF	AB	5,646,949	07/08/1997	Bruce, Jr. et al	37	127	06/04/1996
1PF	AC	5,572,666	11/05/1996	Whitman	395	183.08	03/28/1995
1PF	AD	5,488,573	01/30/1996	Brown et al	364	578	09/02/1993
1PF	AE	5,455,938	10/03/1995	Ahmed	364	488	09/14/1994
1PF	AF	5,210,861	05/11/1993	Shimoda	395	575	05/30/1990
1PF	AG	4,984,239	01/08/1991	Suzuki et al	371	3	01/04/1989
	AK						

## FOREIGN PATENT DOCUMENTS

		Document No.	Date	Country	Class	Subcl.	Translation?
1PF	AL	JP2001051965A	08/12/1999	Japan	_		No
1PF	AM	JP11232131A	02/13/1998	Japan			No
1PF	AN	JP11230160A	01/16/1998	Japan			NO
IPF	AO	JP10187475A	12/25/1996	Japan	_		No
IPF	AP	JP8166892A	12/13/1994	Japan			No
1PF	AQ	JP01180645	01/13/1988	Japan			No

## OTHER DOCUMENTS

MPF	AR	"A Biased Random Instruction Generation Environment for Architectural Verification of Pipelined Processors", Journal of Electronic Testing: Theory and Applications, pgs. 13-27 (2000), Ta-Chung Chang			
MPF	AS	"Micro Architecture Coverage Directed Generation of Test Programs", Design Automation Conference, June 21-25, 1999, pgs. 175-180			
MPF	AT	"Verification by Behavorial Modeling – A Multiprocessor System Case, Conference on ASIC Proceedings", October 21-24, 1996, pgs 43-45			
MPF	AU	"Automatic Test Program Generation for Pipelined Processors", IEEE/ACM International Conference on CAD-94, November 6-10, 1994, pgs. 580-583			
Examiner:	Mar	Date Considered: 7/6/06			

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformation with MPEP 609; draw line through citation if in conformance and not considered. Include copy of this form with next communication to applicant.